

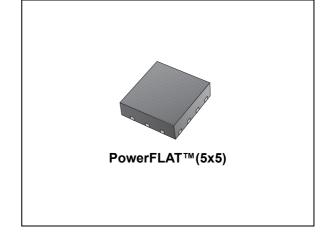
STL3NK40

N-channel 400 V, 4.5 Ω, 2.3 A PowerFLATTM (5x5) SuperMESHTM Power MOSFET

Features

Туре	V _{DSS}	R _{DS(on)} max	I _D ⁽¹⁾	Pw ⁽¹⁾
STL3NK40	400 V	< 5.5 Ω	2.3 A	75 W

- 1. The value is rated according to Rthj-f
- Extremely high dv/dt capability
- Improved ESD capability
- 100% avalanche rated
- Gate charge minimized
- Very low intrinsic capacitances
- Very good manufacturing repeatability



Applications

Switching application

Description

The new SuperMESH™ series of Power MOSFETs is the result of further design improvements on ST's well-established strip-based PowerMESH™ layout. In addition to significantly lower on-resistance, the device offers superior dv/dt capability to ensure optimal performance even in the most demanding applications. The SuperMESH™ devices further complement an already broad range of innovative high voltage MOSFETs, which includes the revolutionary MDmesh™ products.

Figure 1. Internal schematic diagram

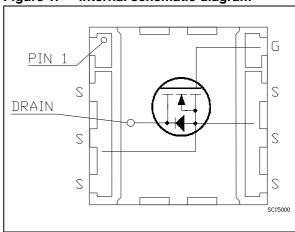


Table 1. Device summary

Order code	Marking	Package	Packaging
STL3NK40	3NK40	PowerFLAT™(5x5)	Tape and reel

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STL3NK40 Electrical ratings

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage (V _{GS} = 0)	400	V
V_{DGR}	Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)	400	V
V_{GS}	Gate- source voltage	± 20	V
I _D ⁽¹⁾	Drain current (continuous) at T _C = 25 ° C (steady state) Drain current (continuous) at T _C = 100°C	0.43 0.27	A A
I _{DM} ⁽¹⁾	Drain current (pulsed)	1.72	Α
P _{TOT} (1)	Total dissipation at T _C = 25 °C (steady state)	2.5	W
P _{TOT} (2)	Total dissipation at T _C = 25 °C (steady state)	75	W
	Derating factor	0.02	W/°C
dv/dt (3)	Peak diode recovery voltage slope	4.5	V/ns
T _{stg} T _j	Storage temperature Max. operating junction temperature	-55 to 150	°C

- 1. When mounted on FR-4 Board of 1 inch², 2 oz Cu (t < 100 s)
- 2. The value is rated according to Rthj-f
- 3. I_{SD} < 0.43 A, di/dt< 200 A/ μ s, V_{DD} < 320 V

Table 3. Thermal resistance

Symbol	Parameter	Value	Unit
Rthj-f	Thermal resistance junction-foot (drain)	1.66	°C/W
Rthj-pcb ⁽¹⁾	Thermal resistance junction-pcb	50	°C/W

^{1.} When mounted on FR-4 Board of 1 inch 2 , 2 oz Cu (t < 100 s)

Table 4. Avalanche data

Symbol	Parameter	Value	Unit
I _{AR}	Avalanche current, repetitive or not-repetitive (pulse width limited by T_j max)	0.43	Α
E _{AS}	Single pulse avalanche energy (starting $T_j = 25$ °C, $I_D = I_{AR}$, $V_{DD} = 50$ V)	60	mJ

2 Electrical characteristics

 $(T_{CASE} = 25 \, ^{\circ}C \text{ unless otherwise specified})$

Table 5. On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 1 mA, V _{GS} = 0	400			٧
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V_{DS} = max rating V_{DS} = max rating, T_{C} = 125 °C			1 50	μ Α μ Α
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 20 V			± 10	μΑ
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 50 \mu A$	0.8	1.6	2	V
R _{DS(on)}	Static drain-source on- resistance	$V_{GS} = 10 \text{ V}, I_D = 0.22 \text{ A}$		4.5	5.5	Ω

Table 6. Dynamic

Symbol	Parameter Test conditions		Min.	Тур.	Max.	Unit
9 _{fs} (1)	Forward transconductance	$V_{DS} = 10 \text{ V}, I_{D} = 0.43 \text{ A}$	-	1.2		S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 25 \text{ V, f} = 1 \text{ MHz,}$ $V_{GS} = 0$	-	128 16 4	200 30 6	pF pF pF
R _G	Gate input resistance	f= 1 MHz Gate DC Bias = 0 Test signal level = 20 mV open drain	-	12		Ω
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V_{DD} = 320 V, I_{D} = 1.4 A, V_{GS} = 10 V (see Figure 10)	-	8.7 0.9 3.8	13	nC nC nC

^{1.} Pulsed: Pulse duration = 300 μ s, duty cycle 1.5%

Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r t _{d(off)} t _f	Turn-on delay time Rise time Turn-off-delay time Fall time	$V_{DD} = 200 \text{ V}, I_{D} = 0.7 \text{ A},$ $R_{G} = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see Figure 14)	-	3 4 18 16	-	ns ns ns ns

Table 8. Source drain diode

Symbol	mbol Parameter Test conditions		Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current		-		0.43	A
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)				1.72	Α
V _{SD} ⁽²⁾	Forward on voltage	$I_{SD} = 0.43 \text{ A}, V_{GS} = 0$	-		1.2	V
t _{rr}	Reverse recovery time	$I_{SD} = 1.4 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$		166		ns
Q_{rr}	Reverse recovery charge	V _{DD} = 20 V	-	300		nC
I _{RRM}	Reverse recovery current	(see Figure 19)		3.6		Α
t _{rr}	Reverse recovery time	$I_{SD} = 1.4 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$		176		ns
Q_{rr}	Reverse recovery charge	$V_{DD} = 20 \text{ V}, T_j = 150 ^{\circ}\text{C}$	-	340		nC
I _{RRM}	Reverse recovery current	(see Figure 19)		3.8		Α

^{1.} Pulse width limited by safe operating area.

^{2.} Pulsed: Pulse duration = 300 μ s, duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

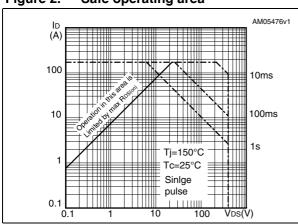


Figure 3. Thermal impedance

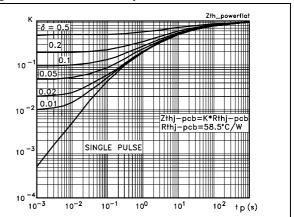


Figure 4. Saturation characteristics

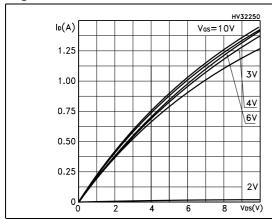


Figure 5. Transfer characteristics

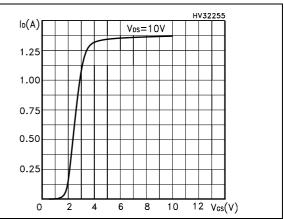


Figure 6. Output characteristics

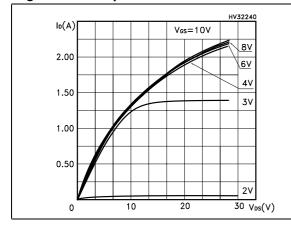
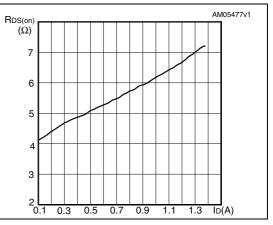
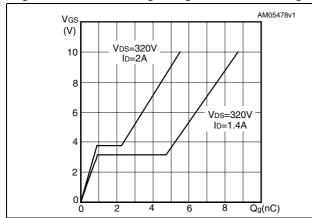


Figure 7. Static drain-source on-resistance



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Figure 8. Gate charge vs gate-source voltage Figure 9. Capacitance variations



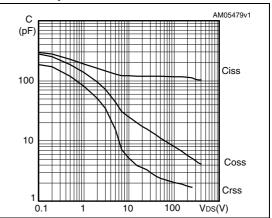


Figure 10. Transconductance

#V32260

grs(S)

2.5

1.5

1.0

0.5

1 2 3 4 5 I_D(A)

Figure 11. Normalized B_{VDSS} vs temperature

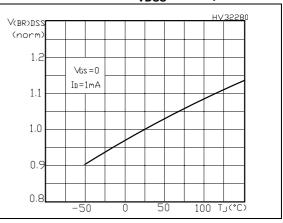
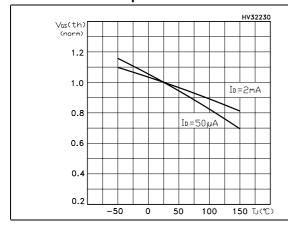
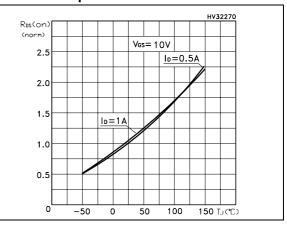


Figure 12. Normalized gate threshold voltage Figure 13. Normalized on-resistance vs vs temperature temperature





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3 Test circuits

Figure 14. Switching times test circuit for resistive load

Figure 15. Gate charge test circuit

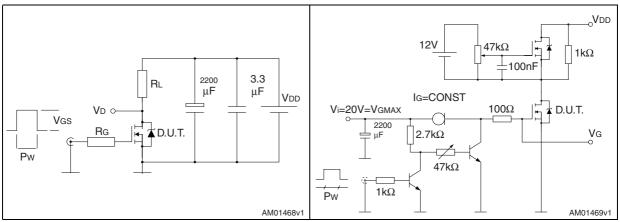


Figure 16. Test circuit for inductive load switching and diode recovery times

Figure 17. Unclamped inductive load test circuit

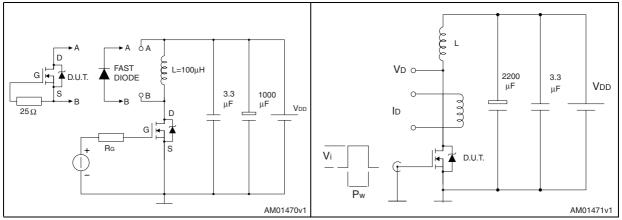
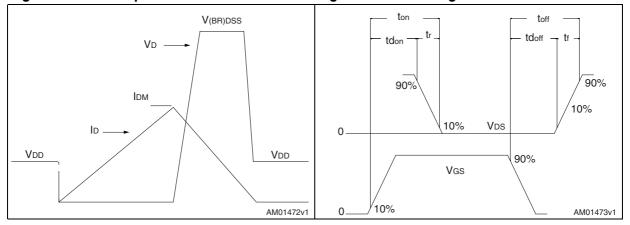


Figure 18. Unclamped inductive waveform

Figure 19. Switching time waveform



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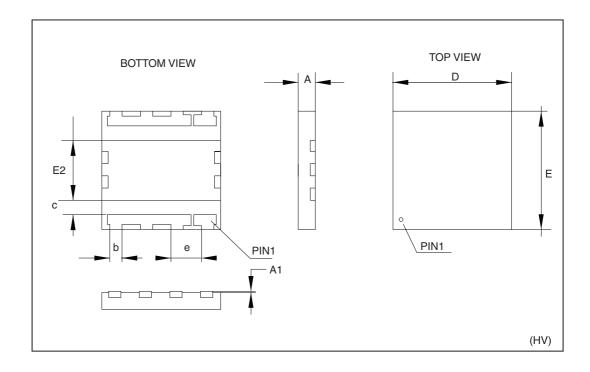
4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.



PowerFLAT ™(5x5) mechanical data

DIM	DIM.		mm.		inch		
DIIVI.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.	
А	0.80	0.90	1.00	0.031	0.035	0.039	
A1		0.02	0.05		0.0007	0.002	
А3		0.24			0.009		
b	0.43	0.51	0.58	0.016	0.020	0.022	
С	0.64	0.71	0.79	0.025	0.027	0.031	
D		5.00			0.19		
Е		5.00			0.19		
E2	2.49	2.57	2.64	0.01	0.10	0.103	
е		1.27			0.05		



STL3NK40 Revision history

5 Revision history

Table 9. Document revision history

Date	Revision	Changes
18-Sep-2009	1	First release



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